

COLLEGE OF ENGINEERING & TECHNOLOGY

Department: Electronics and Communications Engineering

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Short Channel MOSFETs

For 130nm NMOS technology, the device parameters are:

$\mu_0 = 1.35 \times 10^{-2} \text{ m}^2 \text{ V}^{-1} \text{ sec}^{-1}$, $v_{\text{sat}} = 1.3 \times 10^5 \text{ m/sec}$, $n = 2$ for mobility equation.

$t_{\text{ox}} = 3 \text{ nm}$, $N_A = 9 \times 10^{17} \text{ cm}^{-3}$, $x_j = 35 \text{ nm}$, Gate workfunction = 4.05 eV.

Assume: $L_{\text{metallurgical}} = L_{\text{gate}} - 2 \cdot 0.3 \cdot x_j$

Question 1

Assume $V_{\text{ds}} = V_{\text{gs}} = 1.3 \text{ V}$, and $L_{\text{gate}} = 200 \text{ nm}$.

- Find the saturation voltage V_{dsat} (approximate with Long Channel value)
- Find the field at the end of the inversion channel, E_{sat} . Approximate potential with a straight line, and $L_{\text{channel}} \sim L_{\text{metallurgical}}$
- Find the decrease in inversion channel length due to saturation using the 1D model
- Repeat part c using the 2D model
- Improve part b using the new channel length obtained from 1d.
- Improve 1d (again) using the results of 1e.

NOTE: The results of 1e and 1f are the ones to be used in the rest of Sheet 5 and Sheet 6.

- Find the electron velocity at the end of the inversion channel.
- Find the effective mobility, ignoring the vertical effective field effect on mobility
- Find the vertical effective field in the channel

Question 2

Use the Charge Sharing Model

- Find threshold voltage dependence on L for $L_{\text{gate}} = 200 \text{ nm}$ and $1 \mu\text{m}$, for $V_{\text{ds}} = 100 \text{ mV}$ and $V_{\text{ds}} = 1.3 \text{ V}$ (Figure 3.19a).
- Plot the threshold voltage dependence on V_{ds} for between $V_{\text{ds}} = 100 \text{ mV}$ and $V_{\text{ds}} = 1.3 \text{ V}$, for $L_{\text{gate}} = 200 \text{ nm}$ and $L_{\text{gate}} = 1 \mu\text{m}$.

Question 3

- Repeat Question 3 using equations 3.67-3.68, p.182-183
- Tabulate the results for V_{th} with those obtained using the charge sharing model

Question 3

Hint: use the results from Questions 1 and 3

- Plot the I_{ds}/W vs. V_{ds} between $V_{\text{ds}} = 0$ to 1.3 V , $V_{\text{gs}} = 0.7 \text{ V}$ and 1.3 V for $L_{\text{gate}} = 1 \mu\text{m}$.
- Plot the I_{ds}/W vs. V_{ds} between $V_{\text{ds}} = 0$ to 1.3 V , $V_{\text{gs}} = 0.7 \text{ V}$ and 1.3 V for $L_{\text{gate}} = 200 \text{ nm}$.

Hint: Differentiate when there is pinchoff but not velocity saturation in the inversion channel (Channel Length Modulation needs to be taken into consideration for any W/L relationship)

Question 4

Hint: use the V_{th} results from Question 1, and Eqn. 3.40-3.41

For the following 4 cases:

- a) $L_{gate} = 1\mu m$, $V_{ds} = 100mV$, $V_{gs} = 1.3V$.
- b) $L_{gate} = 1\mu m$, $V_{ds} = 1.3V$, $V_{gs} = 1.3V$.
- c) $L_{gate} = 200nm$, $V_{ds} = 100mV$, $V_{gs} = 1.3V$.
- d) $L_{gate} = 200nm$, $V_{ds} = 1.3V$, $V_{gs} = 1.3V$.

- Find $I_{ds OFF}$ and subthreshold slope
- Find the off-state power dissipation between source & drain